

Cypress Semiconductor Package Qualification Report

**QTP# 97454 VERSION 1.0
January, 2002**

**28-lead Windowed Cerpack (W-CerPACK)
Anam Philippines**

CYPRESS TECHNICAL CONTACT FOR QUALIFICATION DATA:

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PACKAGE QUALIFICATION HISTORY

Qual Report	Description of Qualification Purpose	Date Comp
97454	28-lead Windowed Cerpack (W-CerPACK) Package, with die size 106 x 207mils, Anam Philippines	Apr 98

HERMETIC PACKAGE/ASSEMBLY DESCRIPTION	
Package Designation:	T28
Package Outline, Type, or Name:	28-lead Windowed Cerpack (W-CerPACK)
Lead Seal Method/Material:	Glass Seal / KC700 or T187
Mold Compound Flammability Rating:	N/A
Oxygen Rating Index:	N/A
Lead Frame Material:	A42
Lead Finish, Composition / Thickness:	Sn Plate followed by Sn/Pb dip
Die Backside Preparation Method/Metallization:	N/A
Die Separation Method:	Wafer Saw
Die Attach Method:	Ag / Glass
Die Attach Supplier:	QMI
Die Attach Material:	2419MA
Bond Diagram Designation	10-01806
Wire Bond Method:	Wedge
Wire Material/Size:	Al/ 1.25mil
Thermal Resistance Theta JA °C/W:	N/A
Package Cross Section Yes/No:	N/A
Assembly Process Flow:	49-14999
Name/Location of Assembly (prime) facility:	Anam Philippines (PHIL-M)

ELECTRICAL TEST / FINISH DESCRIPTION	
Test Location:	Anam Philippines (PHIL-M)
Fault Coverage:	100%

Note: Please contact a Cypress Representative for other packages availability.

RELIABILITY TESTS PERFORMED PER SPECIFICATION REQUIREMENT

Stress/Test	Test Condition (Temp/Bias)	Result P/F
Temperature Cycle (Military)	MIL-STD-883C, Method 1010, Condition C, -65°C to 150°C	P
Internal Visual	Cypress Spec 25-00017	P
Physical Dimension	Cypress Spec. 25-00031	P
Military Life Test Group C	150C, 5.75V	P
External Visual	Cypress Spec 25-00038	P
Solderability	Cypress Spec 25-00018	P
Salt Atmosphere	Cypress Spec 25-00013/Cypress Spec 25-00038	P
Adhesion of Lead Finish	Cypress Spec. 25-00029	P
Lid Torque	Cypress Spec. 25-00035	P
Thermal Series	MIL-STD-883C, Method 5005	P
Die Shear	Cypress Spec. 12-00292	P
Solderability, Steam Aged	Cypress Spec. 25-00018	P
X-Ray	MIL-STD-883C, Method 2012 / Cypress Spec. 12-00292	P
Lead Integrity	Cypress Spec. 25-00004	P
Mechanical Series	MIL-STD-883C, Method 5005	P
Internal Water Vapor	MIL-STD-883C, Method 1018	P

Reliability Test Data

QTP #: 97454

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
STRESS: PHYSICAL DIMENSIONS							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	15	0	
STRESS: LEAD INTEGRITY							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	4	0	
STRESS: THERMAL SERIES							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	17	0	
STRESS: MECHANICAL SERIES							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	17	0	
STRESS: SALT ATMOSPHERE							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	15	0	
STRESS: INTERNAL WATER VAPOR							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	3	0	
STRESS: ADHESION OF LEAD FINISH							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	3	0	
STRESS: EXTERNAL VISUAL							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	15	0	
STRESS: DIE SHEAR							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	15	0	
STRESS: INTERNAL VISUAL							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	5	0	
STRESS: SOLERABILITY							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	3	0	
STRESS: MILITARY LIFE TEST GROUP C, 150C, 5.75V							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	184	48	0	

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<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
STRESS: X-RAY							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	15	0	
STRESS: LID TORQUE							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	COMP	3	0	
STRESS: TC CONDITION C, 150C TO -65C, MSL1							
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	100	47	0	
CY7C251-TMB (7C251B)	2720542	349705494	PHIL-M	1000	47	0	